

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/788,491	NAKANO ET AL.	
	Examiner	Art Unit	Page 1 of 1
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	B	US-6,094,649	07-2000	Bowen et al.	707/3
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**NON-PATENT DOCUMENTS**

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